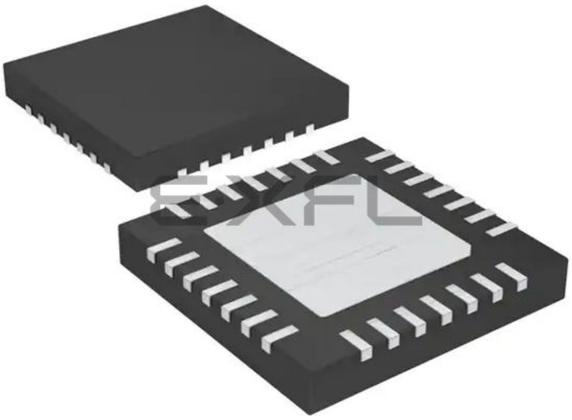

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	22
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 5.25V
Data Converters	A/D 20x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	28-WFQFN Exposed Pad
Supplier Device Package	28-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8ub10f16g-b-qfn28

3.7 Analog

12-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 12-, 10-, and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs.
- Single-ended 12-bit and 10-bit modes.
- Supports an output update rate of 200 ksps samples per second in 12-bit mode or 800 ksps samples per second in 10-bit mode.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal fast-settling reference with two levels (1.65 V and 2.4 V) and support for external reference and signal ground.
- Integrated temperature sensor.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 12 (CMP1) external positive inputs
- Up to 10 (CMP0) or 12 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.10 Bootloader

All devices come pre-programmed with a USB bootloader. This bootloader resides in the code security page and last pages of code flash; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

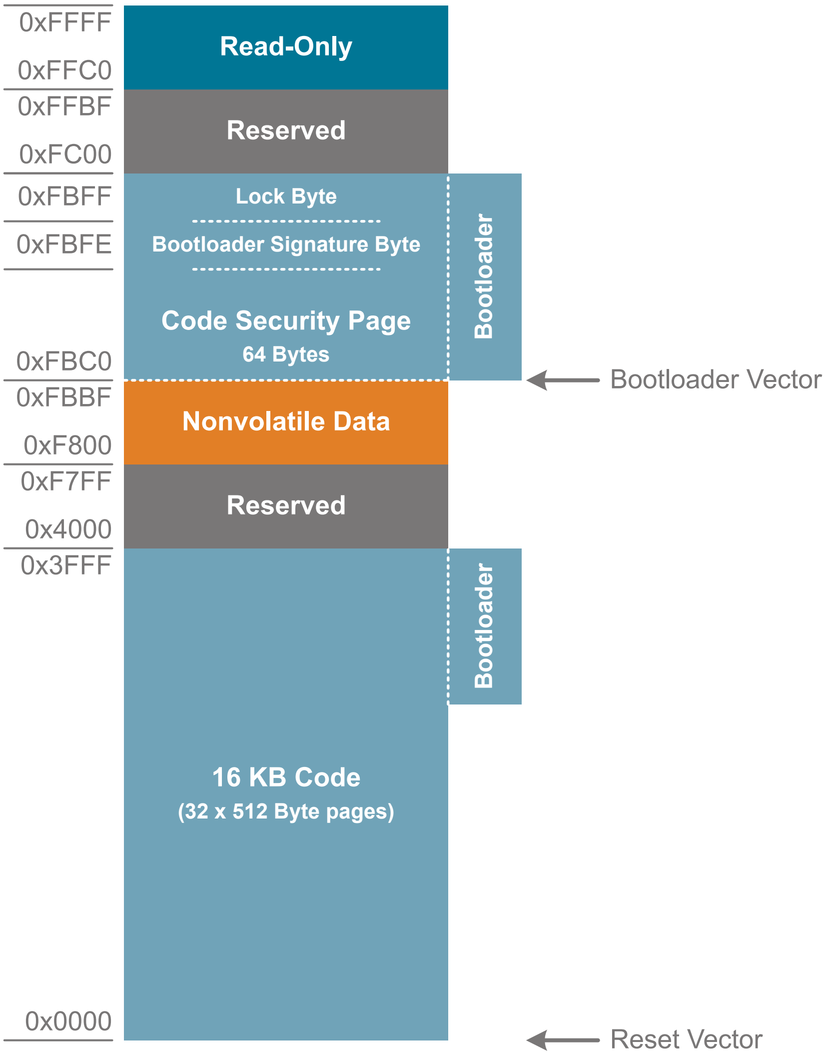

Figure 3.2. Flash Memory Map with Bootloader—16 KB Devices

4.1.2 Power Consumption

Table 4.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current						
Normal Mode-Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 48 MHz [2]	—	8.9	9.8	mA
		F_{SYSCLK} = 24.5 MHz [2]	—	4.3	4.9	mA
		F_{SYSCLK} = 1.53 MHz [2]	—	600	—	μA
		F_{SYSCLK} = 80 kHz [3]	—	145	—	μA
Idle Mode-Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 48 MHz [2]	—	6	6.6	mA
		F_{SYSCLK} = 24.5 MHz [2]	—	2.8	3.2	mA
		F_{SYSCLK} = 1.53 MHz [2]	—	440	—	μA
		F_{SYSCLK} = 80 kHz [3]	—	130	—	μA
Suspend Mode-Core halted and high frequency clocks stopped, Supply monitor off.	I_{DD}	LFO Running	—	125	—	μA
		LFO Stopped	—	120	—	μA
Snooze Mode-Core halted and high frequency clocks stopped. Regulator in low-power state, Supply monitor off.	I_{DD}	LFO Running	—	25	—	μA
		LFO Stopped	—	20	—	μA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	—	μA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	—	μA
Analog Peripheral Supply Currents						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, T_A = 25 °C	—	105	—	μA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 48 MHz, T_A = 25 °C	—	850	—	μA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	4	—	μA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
5V Regulator	I_{VREG}	Normal Mode (SUSEN = 0, BIASENB = 0)	—	245	340	µA
		Suspend Mode (SUSEN = 1, BIASENB = 0)	—	60	100	µA
		Bias Disabled (BIASENB = 1)	—	2.5	10	µA
		Disabled (BIASENB = 1, REG1ENB = 1)	—	2.5	—	nA
USB (USB0) Full-Speed	I_{USB}	Low Energy Mode, 64 byte 1ms IN Interrupt transfers	—	850	—	µA
		Low Energy Mode, 64 byte 1ms OUT Interrupt transfers	—	250	—	µA
		Low Energy Mode, Idle (SOF only)	—	50	—	µA

Note:

1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal LDO regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal LDO regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 always-on power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in burst mode to save power.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}		1.95	2.05	2.15	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on VDD	—	1.2	—	V
		Falling Voltage on VDD	0.75	—	1.36	V
VDD Ramp Time	t_{RMP}	Time to V_{DD} > 2.2 V	10	—	—	µs
Reset Delay from POR	t_{POR}	Relative to $V_{DD} > V_{POR}$	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	50	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	F_{SYSCLK} >1 MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13.5	kHz
VDD Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1] , [2]	t_{WRITE}	One Byte, F_{SYSCLK} = 24.5 MHz	19	20	21	µs
Erase Time[1] , [2]	t_{ERASE}	One Page, F_{SYSCLK} = 24.5 MHz	5.2	5.35	5.5	ms
V_{DD} Voltage During Programming [3]	V_{PROG}		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		20k	100k	—	Cycles

Note:

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold (V_{VDDM}).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUSPENDWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	170	—	ns
Snooze Mode Wake-up Time	$t_{SLEEPWK}$	SYSCLK = HFOSC0 CLKDIV = 0x00	—	12	—	µs

4.1.8 ADC

Table 4.8. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}	12 Bit Mode		12		Bits
		10 Bit Mode		10		Bits
Throughput Rate (High Speed Mode)	f_S	12 Bit Mode	—	—	200	ksps
		10 Bit Mode	—	—	800	ksps
Throughput Rate (Low Power Mode)	f_S	12 Bit Mode	—	—	62.5	ksps
		10 Bit Mode	—	—	250	ksps
Tracking Time	t_{TRK}	High Speed Mode	230	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t_{PWR}		1.2	—	—	μs
SAR Clock Frequency	f_{SAR}	High Speed Mode, Reference is 2.4 V internal	—	—	6.25	MHz
		High Speed Mode, Reference is not 2.4 V internal	—	—	12.5	MHz
		Low Power Mode	—	—	4	MHz
Conversion Time	t_{CNV}	10-Bit Conversion, SAR Clock = 12.25 MHz, System Clock = 24.5 MHz.		1.1		μs
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	5	—	pF
		Gain = 0.5	—	2.5	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	550	—	Ω
Voltage Reference Range	V_{REF}		1	—	V_{IO}	V
Input Voltage Range [1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	$2xV_{REF}$	V
Power Supply Rejection Ratio	$PSRR_{ADC}$		—	70	—	dB
DC Performance						
Integral Nonlinearity	INL	12 Bit Mode	—	±1	±2.3	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode	-1	±0.7	1.9	LSB
		10 Bit Mode	—	±0.2	±0.6	LSB
Offset Error	E_{OFF}	12 Bit Mode, VREF = 1.65 V	-3	0	3	LSB
		10 Bit Mode, VREF = 1.65 V	-2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C

4.1.13 Port I/O

Table 4.13. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	I_{OH} = -7 mA, $V_{IO} \geq 3.0$ V	V_{IO} - 0.7	—	—	V
		I_{OH} = -3.3 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (High Drive)	V_{OL}	I_{OL} = 13.5 mA, $V_{IO} \geq 3.0$ V	—	—	0.6	V
		I_{OL} = 7 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 3.6 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Output High Voltage (Low Drive)	V_{OH}	I_{OH} = -4.75 mA, $V_{IO} \geq 3.0$ V	V_{IO} - 0.7	—	—	V
		I_{OH} = -2.25 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OH} = -1.2 mA, 1.71 V ≤ V_{IO} < 2.2 V	V_{IO} x 0.8	—	—	V
Output Low Voltage (Low Drive)	V_{OL}	I_{OL} = 6.5 mA, $V_{IO} \geq 3.0$ V	—	—	0.6	V
		I_{OL} = 3.5 mA, 2.2 V ≤ V_{IO} < 3.0 V I_{OL} = 1.8 mA, 1.71 V ≤ V_{IO} < 2.2 V	—	—	V_{IO} x 0.2	V
Input High Voltage (all port pins including VBUS)	V_{IH}		V_{IO} - 0.6	—	—	V
Input Low Voltage (all port pins including VBUS)	V_{IL}		—	—	0.6	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current (V_{IN} = 0 V)	I_{PU}	V_{DD} = 3.6	-30	-20	-10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	GND < V_{IN} < V_{IO}	-1.1	—	1.1	µA
Input Leakage Current with V_{IN} above V_{IO}	I_{LK}	V_{IO} < V_{IN} < V_{IO}+2.0 V	0	5	150	µA

4.3 Absolute Maximum Ratings

Stresses above those listed in 4.3 Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO[2]	V_{IO}		GND-0.3	4.2	V
Voltage on VREGIN	V_{REGIN}		GND-0.3	5.8	V
Voltage on D+ or D-	V_{USBD}		GND-0.3	V_{DD}+0.3	V
Voltage on I/O pins (including VBUS / P3.1) or RSTb	V_{IN}	V_{IO} > 3.3 V	GND-0.3	5.8	V
		V_{IO} < 3.3 V	GND-0.3	V_{IO}+2.5	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J		-40	105	°C

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. On devices without a VIO pin, $V_{IO} = V_{DD}$

4.4 Typical Performance Curves

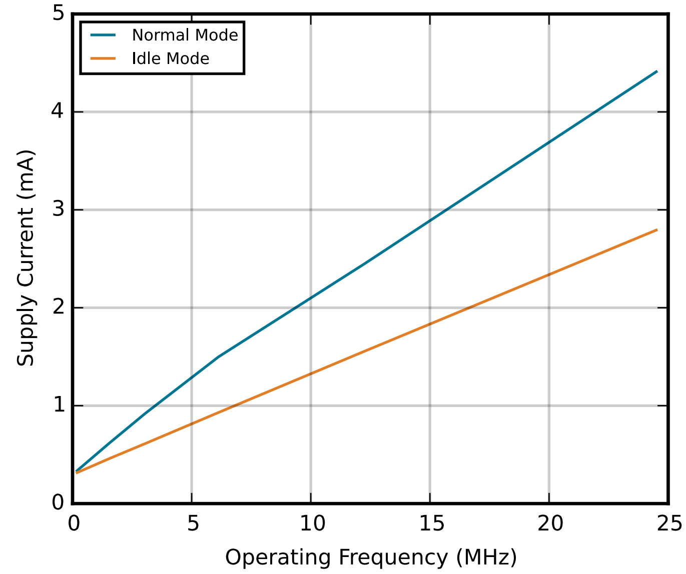

Figure 4.1. Typical Operating Supply Current using HFOSC0

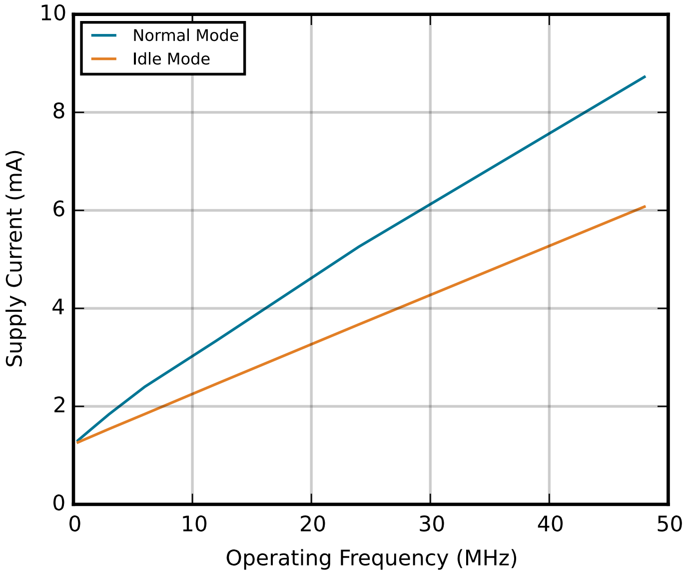

Figure 4.2. Typical Operating Supply Current using HFOSC1

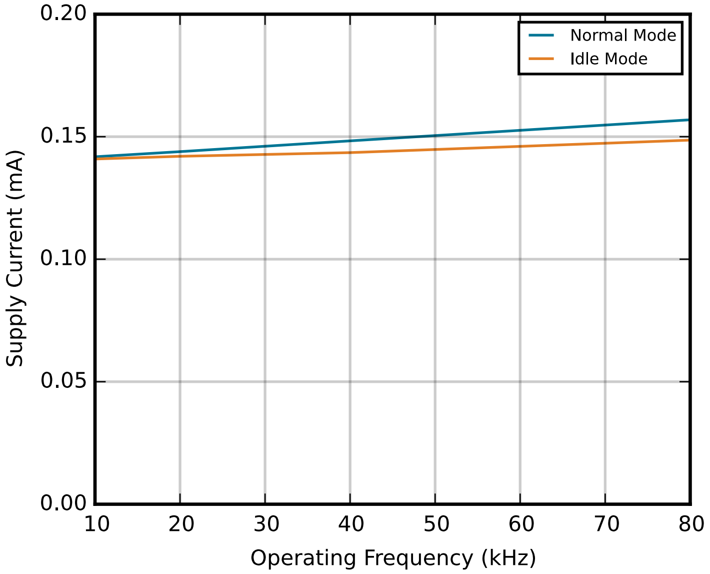

Figure 4.3. Typical Operating Supply Current using LFOSC

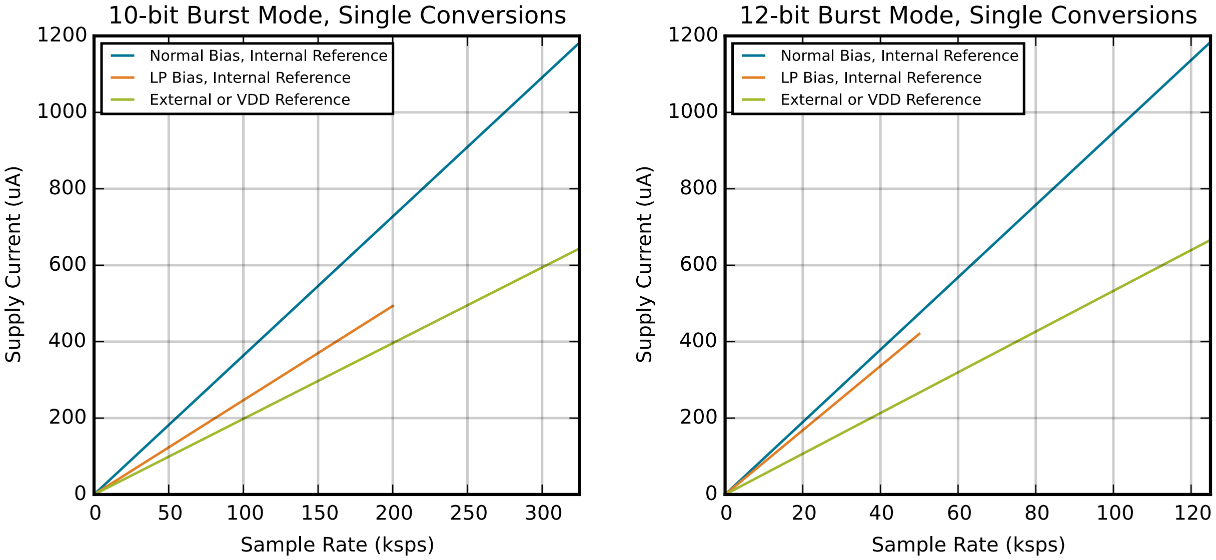

Figure 4.4. Typical ADC0 and Internal Reference Supply Current in Burst Mode

6. Pin Definitions

6.1 EFM8UB1x-QFN28 Pin Definitions

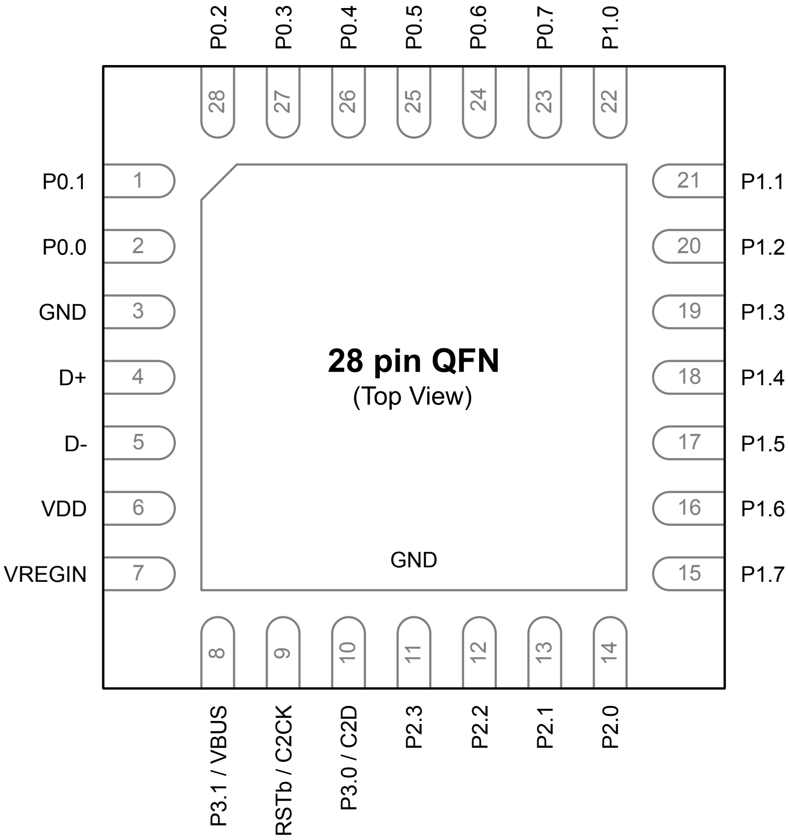

Figure 6.1. EFM8UB1x-QFN28 Pinout

Table 6.1. Pin Definitions for EFM8UB1x-QFN28

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF
3	GND	Ground			
4	D+	USB Data Positive			ADC0.28
5	D-	USB Data Negative			ADC0.29
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	P3.1	Multifunction I/O		VBUS	
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
11	P2.3	Multifunction I/O	Yes	P2MAT.3	ADC0.23 CMP1P.12 CMP1N.12
12	P2.2	Multifunction I/O	Yes	P2MAT.2	ADC0.22 CMP1P.11 CMP1N.11
13	P2.1	Multifunction I/O	Yes	P2MAT.1	ADC0.21 CMP1P.10 CMP1N.10
14	P2.0	Multifunction I/O	Yes	P2MAT.0	ADC0.20 CMP1P.9 CMP1N.9
15	P1.7	Multifunction I/O	Yes	P1MAT.7	ADC0.15 CMP1P.7 CMP1N.7
16	P1.6	Multifunction I/O	Yes	P1MAT.6 I2C0_SCL	ADC0.14 CMP1P.6 CMP1N.6
17	P1.5	Multifunction I/O	Yes	P1MAT.5 I2C0_SDA	ADC0.13 CMP1P.5 CMP1N.5

6.3 EFM8UB1x-QFN20 Pin Definitions

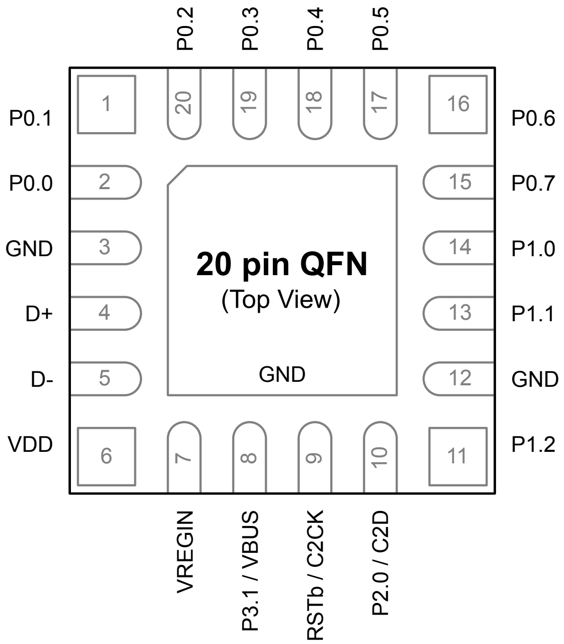

Figure 6.3. EFM8UB1x-QFN20 Pinout

Table 6.3. Pin Definitions for EFM8UB1x-QFN20

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1 AGND
2	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0 VREF

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
3	GND	Ground			
4	D+	USB Data Positive			ADC0.28
5	D-	USB Data Negative			ADC0.29
6	VDD	Supply Power Input / 5V Regulator Output			
7	VREGIN	5V Regulator Input			
8	P3.1	Multifunction I/O		VBUS	
9	RST / C2CK	Active-low Reset / C2 Debug Clock			
10	P2.0 / C2D	Multifunction I/O / C2 Debug Data	Yes		
11	P1.2	Multifunction I/O	Yes	P1MAT.2 I2C0_SCL	ADC0.10 CMP1P.4 CMP1N.4
12	GND	Ground			
13	P1.1	Multifunction I/O	Yes	P1MAT.1 I2C0_SDA	ADC0.9 CMP1P.3 CMP1N.3
14	P1.0	Multifunction I/O	Yes	P1MAT.0	ADC0.8 CMP1P.2 CMP1N.2
15	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 CMP1P.1 CMP1N.1 CMP0P.7 CMP0N.7
16	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP1P.0 CMP1N.0 CMP0P.6 CMP0N.6
17	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX	ADC0.5 CMP0P.5 CMP0N.5

7. QFN28 Package Specifications

7.1 QFN28 Package Dimensions

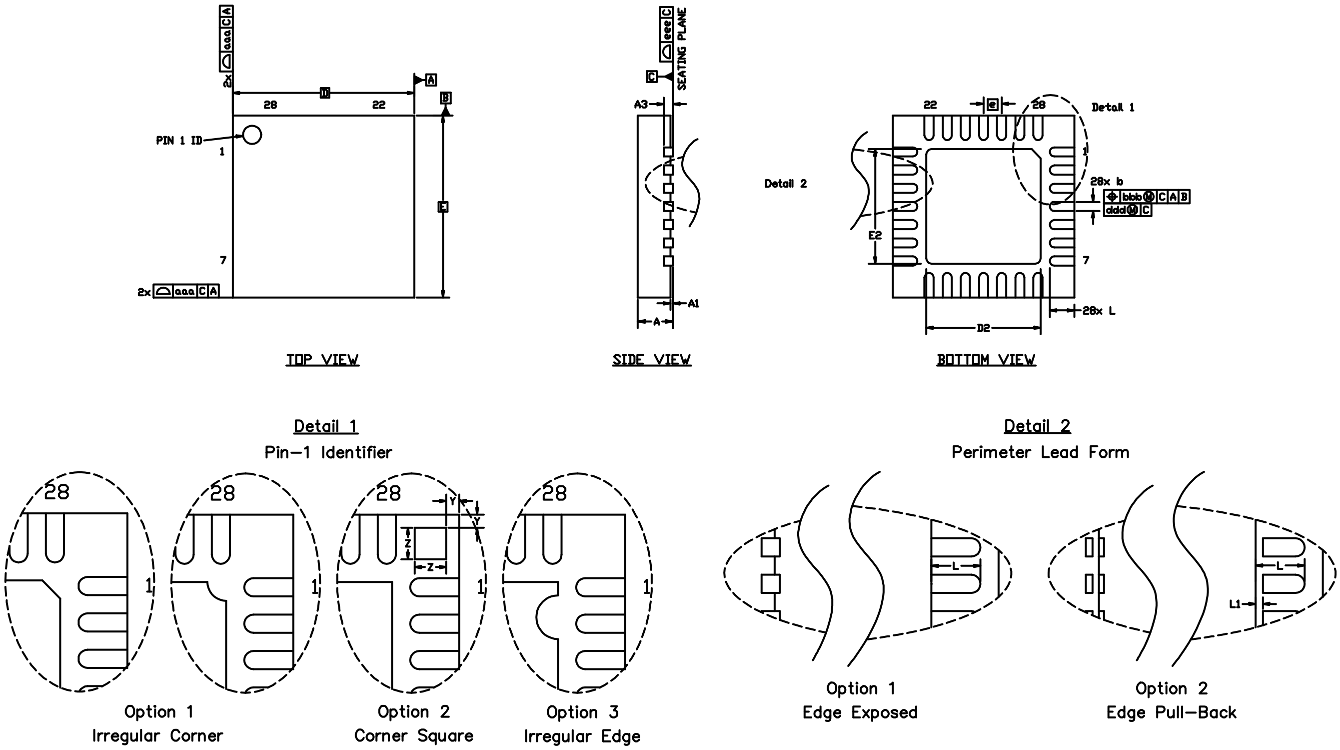

Figure 7.1. QFN28 Package Drawing

Table 7.1. QFN28 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	—	0.05
A3		0.20 REF	
b	0.20	0.25	0.30
D	4.90	5.00	5.10
D2	3.15	3.25	3.35
e		0.50 BSC	
E	4.90	5.00	5.10
E2	3.15	3.25	3.35
L	0.45	0.55	0.65
aaa		0.15	
bbb		0.10	
ddd		0.05	

8. QSOP24 Package Specifications

8.1 QSOP24 Package Dimensions

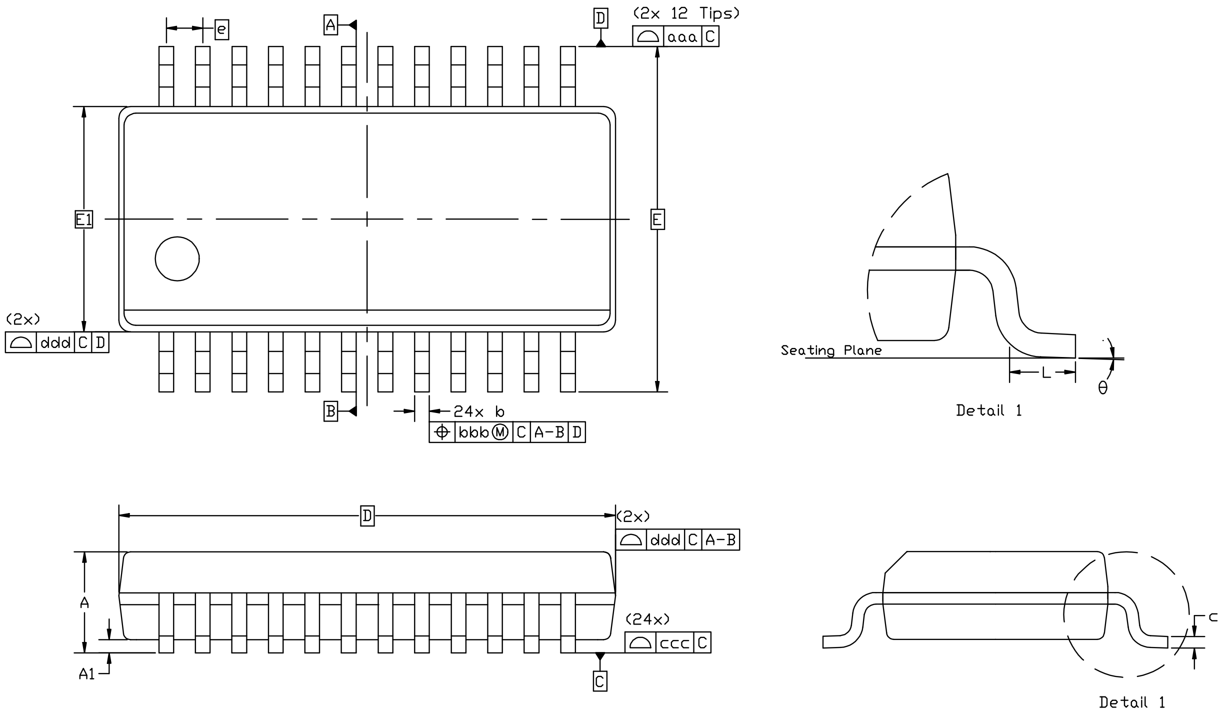

Figure 8.1. QSOP24 Package Drawing

Table 8.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0º	—	8º

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9. QFN20 Package Specifications

9.1 QFN20 Package Dimensions

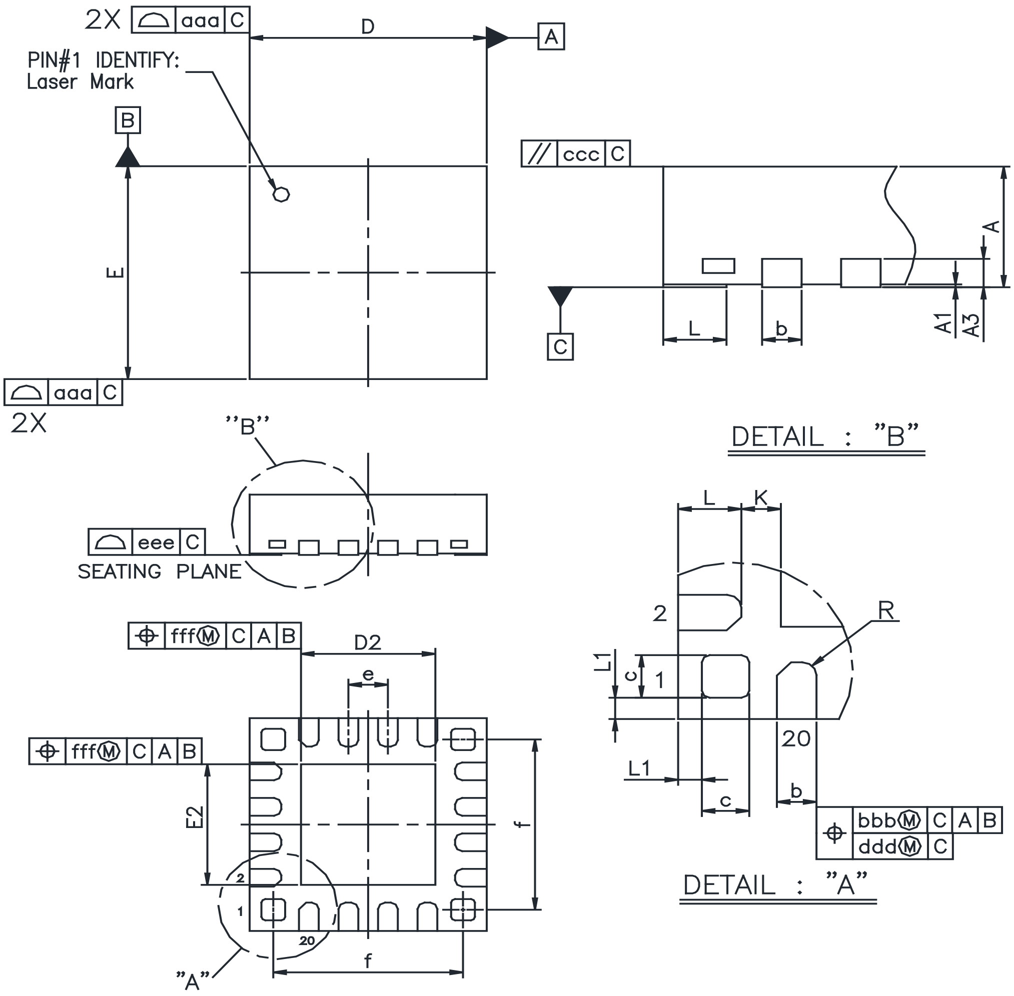

Figure 9.1. QFN20 Package Drawing

Table 9.1. QFN20 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3		0.20 REF	
b	0.18	0.25	0.30
c	0.25	0.30	0.35
D		3.00 BSC	
D2	1.6	1.70	1.80
e		0.50 BSC	

9.2 QFN20 PCB Land Pattern

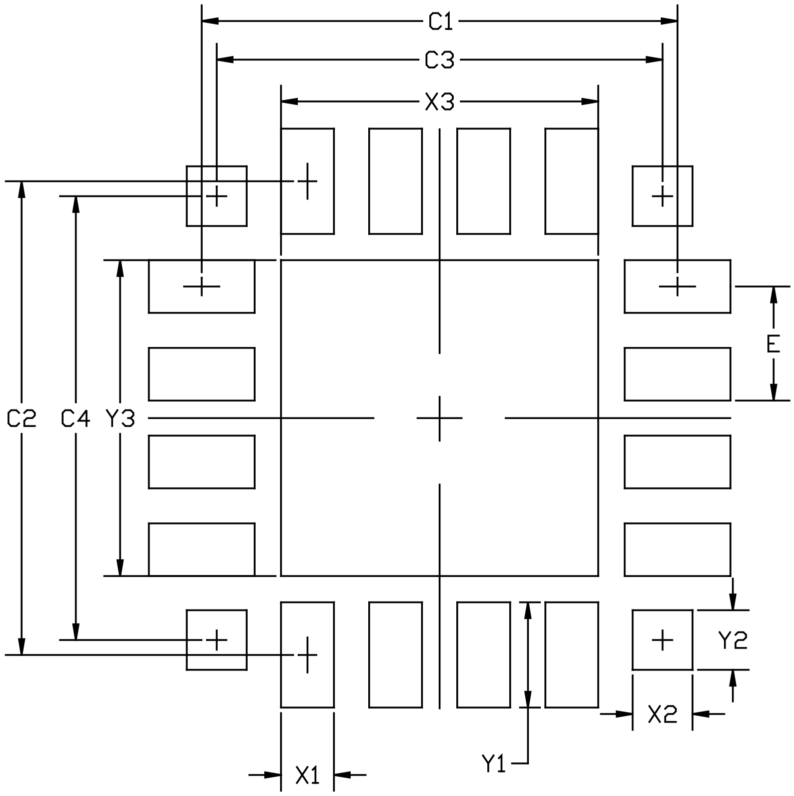

Figure 9.2. QFN20 PCB Land Pattern Drawing

Table 9.2. QFN20 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.10	
C2	3.10	
C3	2.50	
C4	2.50	
E	0.50	
X1	0.30	
X2	0.25	0.35
X3	1.80	
Y1	0.90	
Y2	0.25	0.35
Y3	1.80	

10. Revision History

10.1 Revision 1.1

December 16, 2015

Updated 3.2 Power to properly reflect that a comparator falling edge wakes the device from Suspend and Snooze.

Added Note 4 to Table 4.1 Recommended Operating Conditions on page 12.

Added 5.3 Debug.

10.2 Revision 1.0

Updated any TBD numbers in 4.1 Electrical Characteristics and adjusted various specifications.

Updated VOH and VOL graphs in Figure 4.6 Typical V_{OH} Curves on page 28 and Figure 4.7 Typical V_{OL} Curves on page 28 and updated the VOH and VOL specifications in Table 4.13 Port I/O on page 22.

Added more information to 3.10 Bootloader.

Updated part numbers to Revision C.

10.3 Revision 0.3

Updated QFN20 packaging and landing diagram dimensions.

Updated QFN28 D and E minimum value.

Updated some characterization TBD values.

Added maximum allowable voltages on D+ and D- and added VBUS / P3.1 to the standard I/O row in Table 4.16 Absolute Maximum Ratings on page 24.

Added a diagram to 5.1 Power for cases when the internal 5 V-to-3.3 V regulator is not used.

Updated the 5 V-to-3.3 V regulator Electrical Characteristics table.

Added Stop mode to the Power Modes table in 3.2 Power.

10.4 Revision 0.2

Initial release.